


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574010	<b>Applicant(s)/Patent Under Reexamination</b>  NAKANE, YOSHIHIDE
	<b>Examiner</b>  KEVIN LAU	<b>Art Unit</b>  4147

SEARCHED			
Class	Subclass	Date	Examiner
340	5.72, 5.65, 5.52, 5.42	3-23-2009	KL

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with George Bugg	3-31-2009	KL
Inventor name search	4-2-2009	KL
Searched in subclasses (340/426.1, 425.5, 539.11, 539.1, 531, 500, 5.51, 5.2, 5.1, 825, 5.4, 5.6 and 307/10.2, 10.1, 9.1)	3-23-2009	KL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--